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Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	533MHz
Co-Processors/DSP	Communications; QUICC Engine, Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	740-LBGA
Supplier Device Package	740-TBGA (37.5x37.5)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8360evvajdga

This figure shows the MPC8358E block diagram.

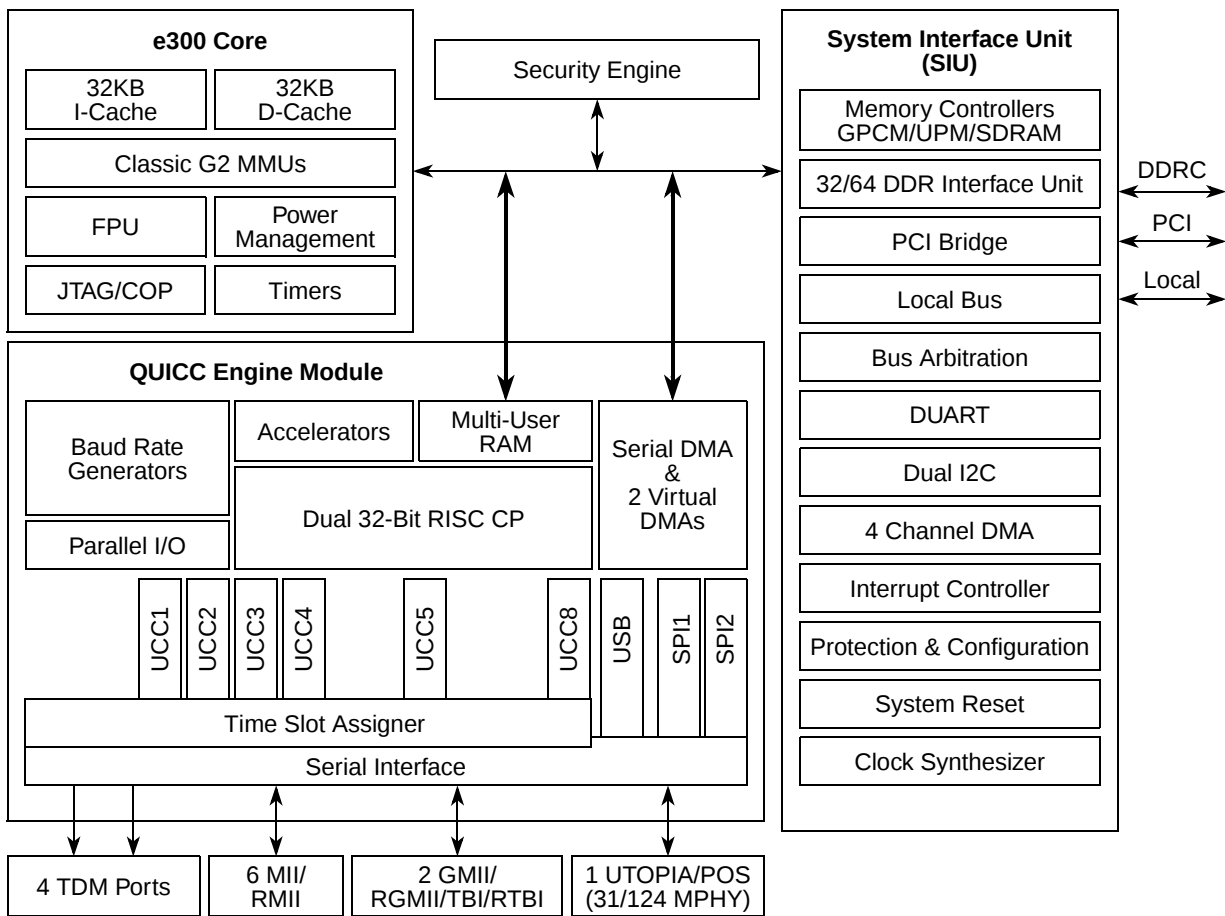


Figure 2. MPC8358E Block Diagram

Major features of the MPC8360E/58E are as follows:

- e300 PowerPC processor core (enhanced version of the MPC603e core)
 - Operates at up to 667 MHz (for the MPC8360E) and 400 MHz (for the MPC8358E)
 - High-performance, superscalar processor core
 - Floating-point, integer, load/store, system register, and branch processing units
 - 32-Kbyte instruction cache, 32-Kbyte data cache
 - Lockable portion of L1 cache
 - Dynamic power management
 - Software-compatible with the Freescale processor families implementing the Power Architecture™ technology
- QUICC Engine unit
 - Two 32-bit RISC controllers for flexible support of the communications peripherals, each operating up to 500 MHz (for the MPC8360E) and 400 MHz (for the MPC8358E)
 - Serial DMA channel for receive and transmit on all serial channels
 - QUICC Engine module peripheral request interface (for SEC, PCI, IEEE Std. 1588™)
 - Eight universal communication controllers (UCCs) on the MPC8360E and six UCCs on the MPC8358E supporting the following protocols and interfaces (not all of them simultaneously):
 - IEEE 1588 protocol supported

- Programmable highest priority request
- Four groups of interrupts with programmable priority
- External and internal interrupts directed to communication processor
- Redirects interrupts to external $\overline{\text{INTA}}$ pin when in core disable mode
- Unique vector number for each interrupt source
- Dual industry-standard I²C interfaces
 - Two-wire interface
 - Multiple master support
 - Master or slave I²C mode support
 - On-chip digital filtering rejects spikes on the bus
 - System initialization data is optionally loaded from I²C-1 EPROM by boot sequencer embedded hardware
- DMA controller
 - Four independent virtual channels
 - Concurrent execution across multiple channels with programmable bandwidth control
 - All channels accessible by local core and remote PCI masters
 - Misaligned transfer capability
 - Data chaining and direct mode
 - Interrupt on completed segment and chain
 - DMA external handshake signals: $\overline{\text{DMA_DREQ}}[0:3]/\overline{\text{DMA_DACK}}[0:3]/\overline{\text{DMA_DONE}}[0:3]$. There is one set for each DMA channel. The pins are multiplexed to the parallel IO pins with other QE functions.
- DUART
 - Two 4-wire interfaces (Rx/D, Tx/D, RTS, CTS)
 - Programming model compatible with the original 16450 UART and the PC16550D
- System timers
 - Periodic interrupt timer
 - Real-time clock
 - Software watchdog timer
 - Eight general-purpose timers
- IEEE Std. 1149.1TM-compliant, JTAG boundary scan
- Integrated PCI bus and SDRAM clock generation

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8360E/58E. The device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

Table 1. Absolute Maximum Ratings¹ (continued)

Characteristic	Symbol	Max Value	Unit	Notes
Storage temperature range	T _{STG}	–55 to 150	°C	—

Notes:

- Functional and tested operating conditions are given in [Table 2](#). Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- (M,L,O)V_{IN} and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 3](#).
- OV_{IN} on the PCI interface may overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in [Figure 4](#).

2.1.2 Power Supply Voltage Specification

This table provides the recommended operating conditions for the device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit	Notes
Core and PLL supply voltage for MPC8358 Device Part Number with Processor Frequency label of AD=266MHz and AG=400MHz & QUICC Engine Frequency label of E=300MHz & G=400MHz MPC8360 Device Part Number with Processor Frequency label of AG=400MHz and AJ=533MHz & QUICC Engine Frequency label of G=400MHz	V _{DD} & AV _{DD}	1.2 V ± 60 mV	V	1, 3
Core and PLL supply voltage for MPC8360 Device Part Number with Processor Frequency label of AL=667MHz and QUICC Engine Frequency label of H=500MHz	V _{DD} & AV _{DD}	1.3 V ± 50 mV	V	1, 3
DDR and DDR2 DRAM I/O supply voltage DDR DDR2	GV _{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	—
Three-speed Ethernet I/O supply voltage	LV _{DD0}	3.3 V ± 330 mV 2.5 V ± 125 mV	V	—
Three-speed Ethernet I/O supply voltage	LV _{DD1}	3.3 V ± 330 mV 2.5 V ± 125 mV	V	—
Three-speed Ethernet I/O supply voltage	LV _{DD2}	3.3 V ± 330 mV 2.5 V ± 125 mV	V	—

This figure shows the undershoot and overshoot voltage of the PCI interface of the device for the 3.3-V signals, respectively.

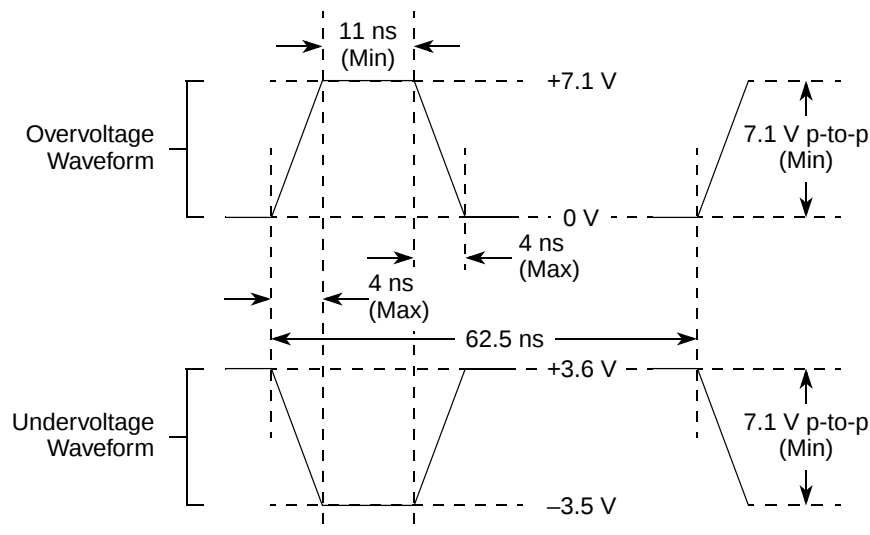


Figure 4. Maximum AC Waveforms on PCI interface for 3.3-V Signaling

2.1.3 Output Driver Characteristics

This table provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Output Impedance (Ω)	Supply Voltage
Local bus interface utilities signals	42	$OV_{DD} = 3.3\text{ V}$
PCI signals	25	
PCI output clocks (including PCI_SYNC_OUT)	42	
DDR signal	20 36 (half-strength mode) ¹	$GV_{DD} = 2.5\text{ V}$
DDR2 signal	18 36 (half-strength mode) ¹	$GV_{DD} = 1.8\text{ V}$
10/100/1000 Ethernet signals	42	$LV_{DD} = 2.5/3.3\text{ V}$
DUART, system control, I ² C, SPI, JTAG	42	$OV_{DD} = 3.3\text{ V}$
GPIO signals	42	$OV_{DD} = 3.3\text{ V}$ $LV_{DD} = 2.5/3.3\text{ V}$

Note:

1. DDR output impedance values for half strength mode are verified by design and not tested.

2.2 Power Sequencing

This section details the power sequencing considerations for the MPC8360E/58E.

2.2.1 Power-Up Sequencing

MPC8360E/58E does not require the core supply voltage (V_{DD} and AV_{DD}) and I/O supply voltages (GV_{DD} , LV_{DD} , and OV_{DD}) to be applied in any particular order. During the power ramp up, before the power supplies are stable and if the I/O voltages are supplied before the core voltage, there may be a period of time that all input and output pins are actively be driven and cause contention and excessive current from 3A to 5A. In order to avoid actively driving the I/O pins and to eliminate excessive current draw, apply the core voltage (V_{DD}) before the I/O voltage (GV_{DD} , LV_{DD} , and OV_{DD}) and assert $\overline{PORESET}$ before the power supplies fully ramp up. In the case where the core voltage is applied first, the core voltage supply must rise to 90% of its nominal value before the I/O supplies reach 0.7 V, see this figure.

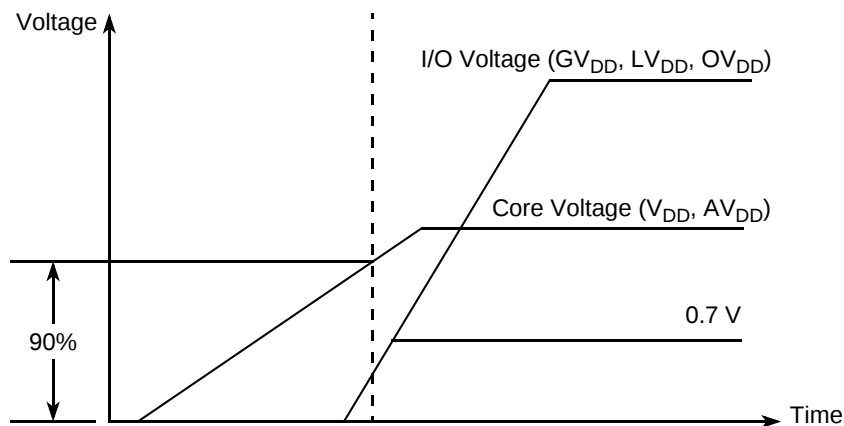


Figure 5. Power Sequencing Example

I/O voltage supplies (GV_{DD} , LV_{DD} , and OV_{DD}) do not have any ordering requirements with respect to one another.

2.2.2 Power-Down Sequencing

The MPC8360E/58E does not require the core supply voltage and I/O supply voltages to be powered down in any particular order.

3 Power Characteristics

The estimated typical power dissipation values are shown in these tables.

Table 4. MPC8360E TBGA Core Power Dissipation¹

Core Frequency (MHz)	CSB Frequency (MHz)	QUICC Engine Frequency (MHz)	Typical	Maximum	Unit	Notes
266	266	500	5.0	5.6	W	2, 3, 5
400	266	400	4.5	5.0	W	2, 3, 4
533	266	400	4.8	5.3	W	2, 3, 4
667	333	400	5.8	6.3	W	3, 6, 7, 8
500	333	500	5.9	6.4	W	3, 6, 7, 8

This figure provides the AC test load for the DDR bus.

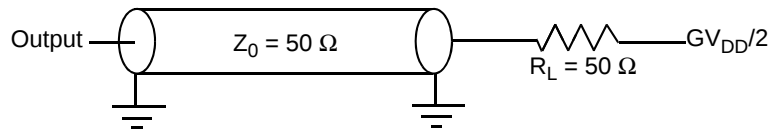


Figure 8. DDR AC Test Load

Table 22. DDR and DDR2 SDRAM Measurement Conditions

Symbol	DDR	DDR2	Unit	Notes
V_{TH}	$MV_{REF} \pm 0.31 V$	$MV_{REF} \pm 0.25 V$	V	1
V_{OUT}	$0.5 \times GV_{DD}$	$0.5 \times GV_{DD}$	V	2

Notes:

1. Data input threshold measurement point.
2. Data output measurement point.

This figure shows the DDR SDRAM output timing diagram for source synchronous mode.

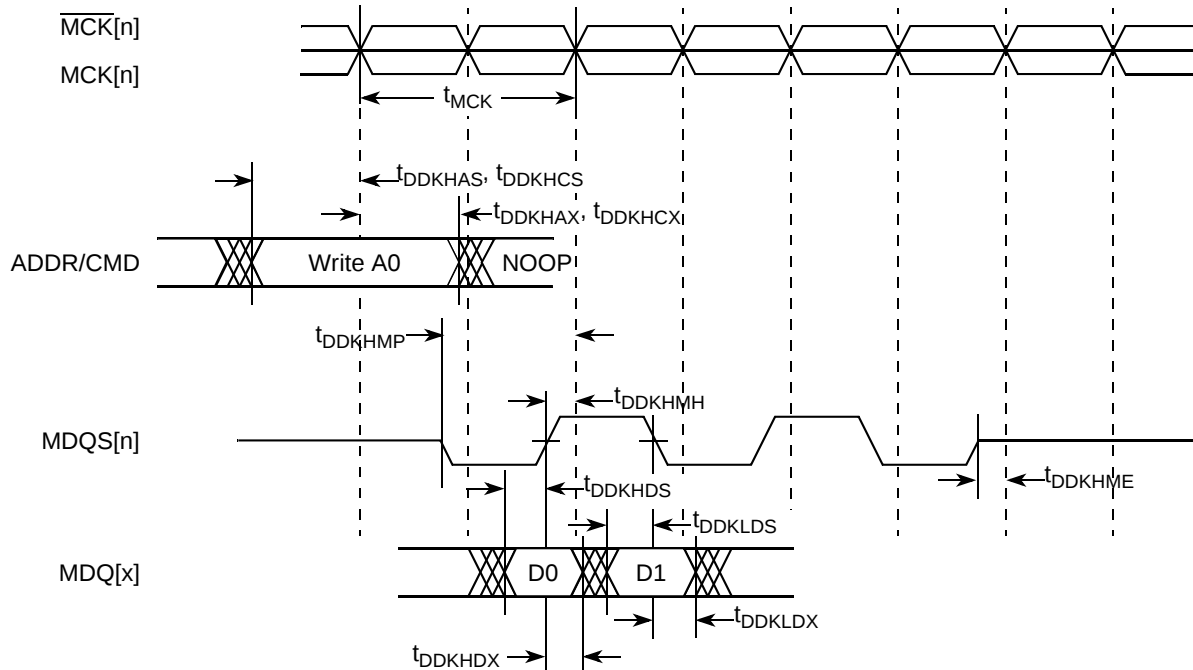


Figure 9. DDR SDRAM Output Timing Diagram for Source Synchronous Mode

8.2.4.2 TBI Receive AC Timing Specifications

This table provides the TBI receive AC timing specifications.

Table 34. TBI Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
PMA_RX_CLK clock period	t_{TRX}	—	16.0	—	ns	—
PMA_RX_CLK skew	t_{SKTRX}	7.5	—	8.5	ns	—
RX_CLK duty cycle	t_{TRXH}/t_{TRX}	40	—	60	%	—
RCG[9:0] setup time to rising PMA_RX_CLK	t_{TRDVKH}	2.5	—	—	ns	2
RCG[9:0] hold time to rising PMA_RX_CLK	t_{TRDXKH}	1.0	—	—	ns	2
RX_CLK clock rise time, V _{IL} (min) to V _{IH} (max)	t_{TRXR}	0.7	—	2.4	ns	—
RX_CLK clock fall time, V _{IH} (max) to V _{IL} (min)	t_{TRXF}	0.7	—	2.4	ns	—

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
- Setup and hold time of even numbered RCG are measured from rising edge of PMA_RX_CLK1. Setup and hold time of odd numbered RCG are measured from rising edge of PMA_RX_CLK0.

This figure shows the TBI receive AC timing diagram.

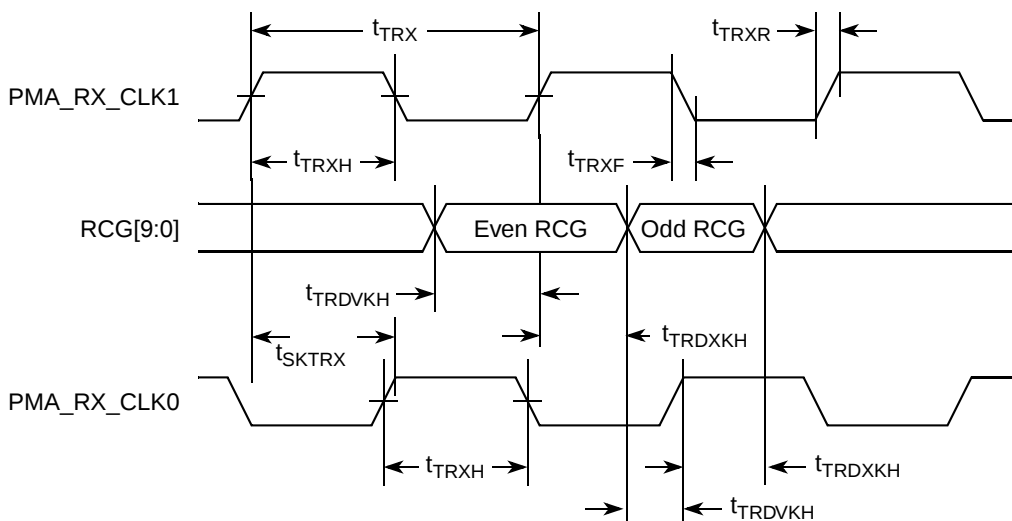


Figure 19. TBI Receive AC Timing Diagram

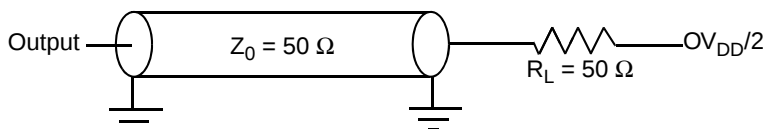
Table 41. Local Bus General Timing Parameters—DLL Bypass Mode⁹ (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus clock to output valid	t_{LBKHOV}	—	3	ns	3
Local bus clock to output high impedance for LAD/LDP	t_{LBKHOZ}	—	4	ns	8

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHGX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to falling edge of LCLK0 (for all outputs and for $\overline{LGTA}$ and LUPWAIT inputs) or rising edge of LCLK0 (for all other inputs).
3. All signals are measured from $OV_{DD}/2$ of the rising/falling edge of LCLK0 to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ should be used when RCWH[LALE] is not set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
6. $t_{LBOTOT2}$ should be used when RCWH[LALE] is set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
7. $t_{LBOTOT3}$ should be used when RCWH[LALE] is set and when the load on LALE output pin equals to the load on LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
9. DLL bypass mode is not recommended for use at frequencies above 66 MHz.

This figure provides the AC test load for the local bus.


Figure 22. Local Bus C Test Load

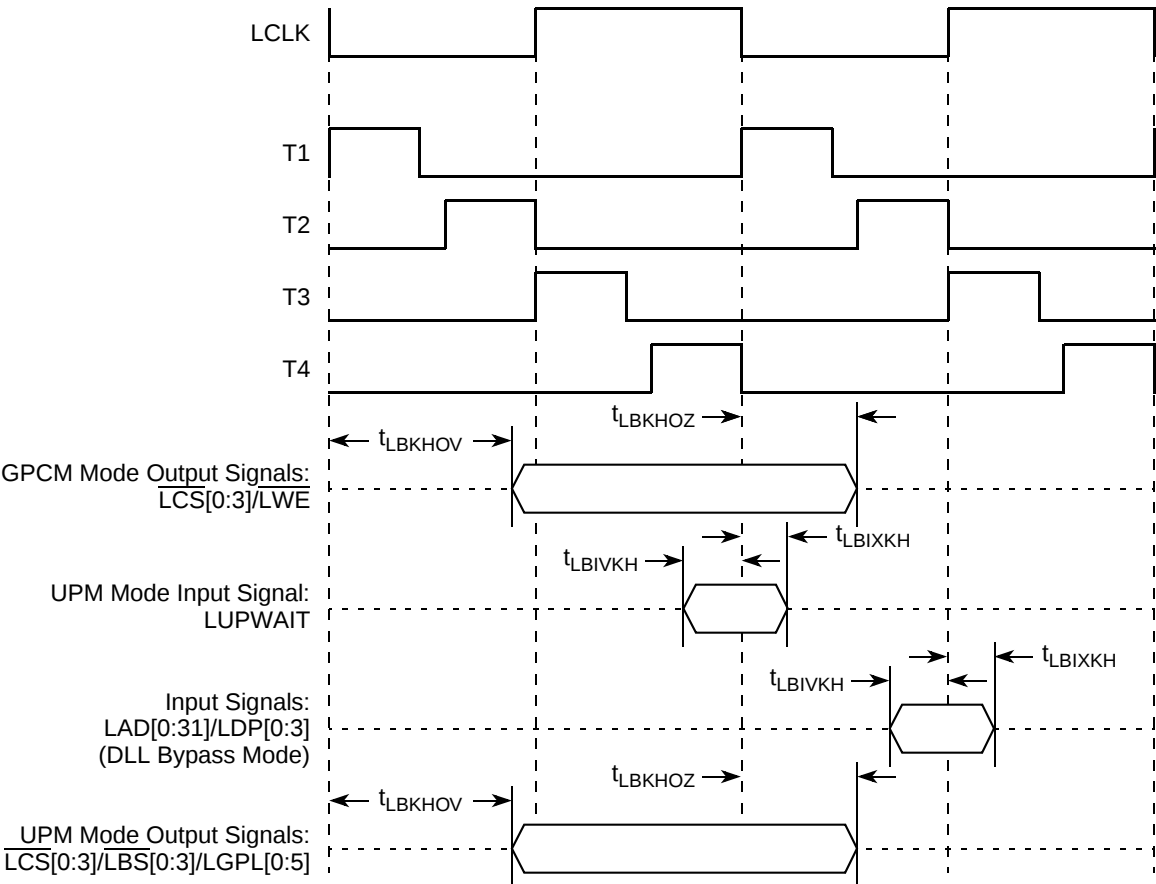


Figure 27. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4 (DLL Bypass Mode)

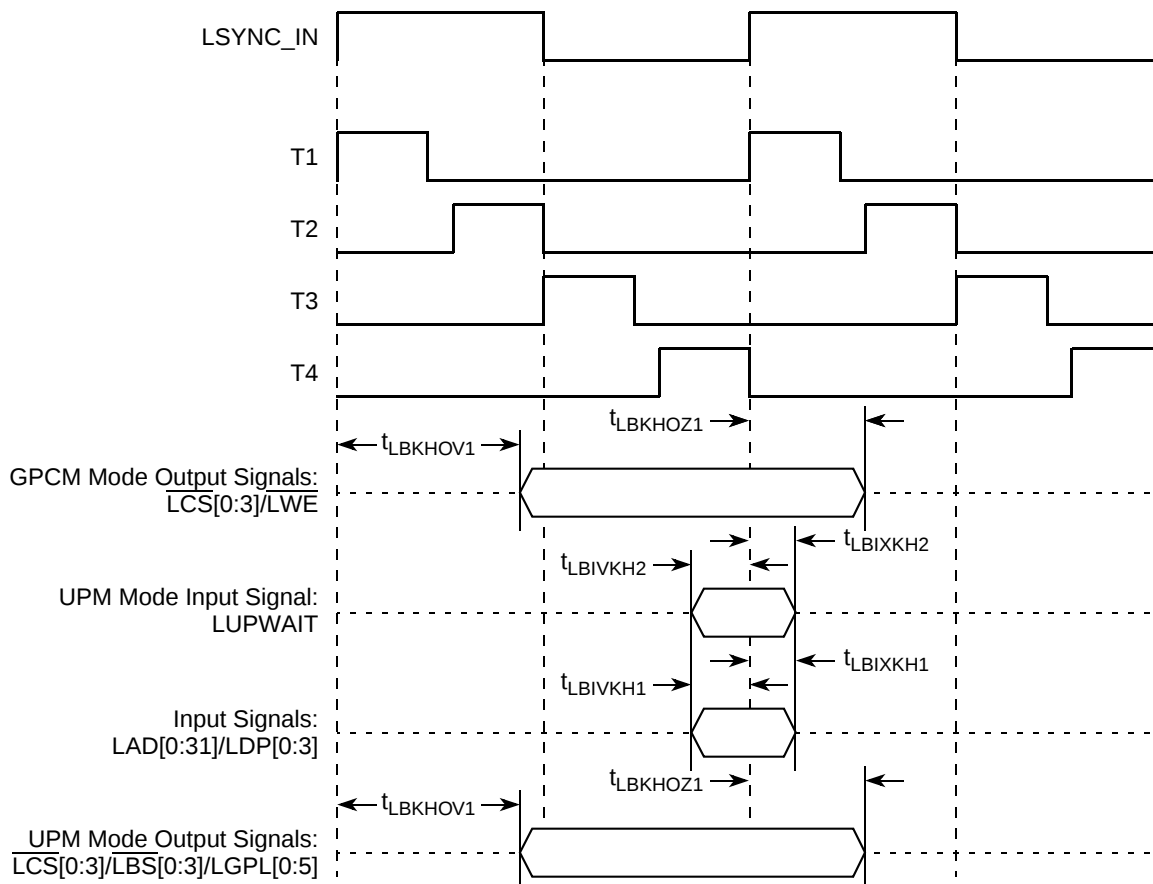


Figure 28. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4 (DLL Enabled)

10 JTAG

This section describes the DC and AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the MPC8360E/58E.

10.1 JTAG DC Electrical Characteristics

This table provides the DC electrical characteristics for the IEEE 1149.1 (JTAG) interface of the device.

Table 42. JTAG interface DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	$I_{OH} = -6.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 6.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V
Input high voltage	V_{IH}	—	2.5	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq OV_{DD}$	—	± 10	μA

11.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interface of the device.

Table 45. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 44).

Parameter	Symbol ¹	Min	Max	Unit	Note
SCL clock frequency	f_{I2C}	0	400	kHz	2
Low period of the SCL clock	t_{I2CL}	1.3	—	μs	—
High period of the SCL clock	t_{I2CH}	0.6	—	μs	—
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs	—
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs	—
Data setup time	t_{I2DVKH}	100	—	ns	3
Data hold time: CBUS compatible masters I ² C bus devices	t_{I2DXKL}	— 0 ²	— 0.9 ³	μs	—
Rise time of both SDA and SCL signals	t_{I2CR}	$20 + 0.1 C_B^4$	300	ns	—
Fall time of both SDA and SCL signals	t_{I2CF}	$20 + 0.1 C_B^4$	300	ns	—
Set-up time for STOP condition	t_{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs	—
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V	—
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V	—

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- The device provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IH} min of the SCL signal) to bridge the undefined region of the falling edge of SCL.
- The maximum t_{I2DVKH} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
- C_B = capacitance of one bus line in pF.

17 TDM/SI

This section describes the DC and AC electrical specifications for the time-division-multiplexed and serial interface of the MPC8360E/58E.

17.1 TDM/SI DC Electrical Characteristics

This table provides the DC electrical characteristics for the device TDM/SI.

Table 57. TDM/SI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	$I_{OH} = -2.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.5	V
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	$0 \text{ V} \leq V_{IN} \leq OV_{DD}$	—	± 10	μA

17.2 TDM/SI AC Timing Specifications

This table provides the TDM/SI input and output AC timing specifications.

Table 58. TDM/SI AC Timing Specifications¹

Characteristic	Symbol ²	Min	Max ³	Unit
TDM/SI outputs—External clock delay	$t_{SEKH OV}$	2	10	ns
TDM/SI outputs—External clock high impedance	$t_{SEKH OX}$	2	10	ns
TDM/SI inputs—External clock input setup time	$t_{SEIV KH}$	5	—	ns
TDM/SI inputs—External clock input hold time	$t_{SEIX KH}$	2	—	ns

Notes:

- Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{SEKH OX}$ symbolizes the TDM/SI outputs external timing (SE) for the time $t_{TDM/SI}$ memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).
- Timings are measured from the positive or negative edge of the clock, according to SIxMR [CE] and SITXCEI [TXCEIx]. Refer *MPC8360E Integrated Communications Processor Reference Manual* for more details.

This figure provides the AC test load for the TDM/SI.

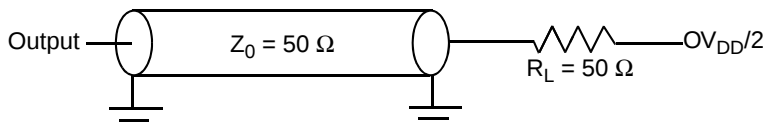


Figure 44. TDM/SI AC Test Load

Figure 45 represents the AC timing from Table 56. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

20.3 Pinout Listings

Refer to AN3097, “MPC8360/MPC8358E PowerQUICC Design Checklist,” for proper pin termination and usage.

This table shows the pin list of the MPC8360E TBGA package.

Table 66. MPC8360E TBGA Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Primary DDR SDRAM Memory Controller Interface				
MEMC1_MDQ[0:31]	AJ34, AK33, AL33, AL35, AJ33, AK34, AK32, AM36, AN37, AN35, AR34, AT34, AP37, AP36, AR36, AT35, AP34, AR32, AP32, AM31, AN33, AM34, AM33, AM30, AP31, AM27, AR30, AT32, AN29, AP29, AN27, AR29	I/O	GV _{DD}	—
MEMC1_MDQ[32:63]/ MEMC2_MDQ[0:31]	AN8, AN7, AM8, AM6, AP9, AN9, AT7, AP7, AU6, AP6, AR4, AR3, AT6, AT5, AR5, AT3, AP4, AM5, AP3, AN3, AN5, AL5, AN4, AM2, AL2, AH5, AK3, AJ2, AJ3, AH4, AK4, AH3	I/O	GV _{DD}	—
MEMC1_MECC[0:4]/ MSRCID[0:4]	AP24, AN22, AM19, AN19, AM24	I/O	GV _{DD}	—
MEMC1_MECC[5]/ MDVAL	AM23	I/O	GV _{DD}	—
MEMC1_MECC[6:7]	AM22, AN18	I/O	GV _{DD}	—
MEMC1_MDM[0:3]	AL36, AN34, AP33, AN28	O	GV _{DD}	—
MEMC1_MDM[4:7]/ MEMC2_MDM[0:3]	AT9, AU4, AM3, AJ6	O	GV _{DD}	—
MEMC1_MDM[8]	AP27	O	GV _{DD}	—
MEMC1_MDQS[0:3]	AK35, AP35, AN31, AM26	I/O	GV _{DD}	—
MEMC1_MDQS[4:7]/ MEMC2_MDQS[0:3]	AT8, AU3, AL4, AJ5	I/O	GV _{DD}	—
MEMC1_MDQS[8]	AP26	I/O	GV _{DD}	—
MEMC1_MBA[0:1]	AU29, AU30	O	GV _{DD}	—
MEMC1_MBA[2]	AT30	O	GV _{DD}	—
MEMC1_MA[0:14]	AU21, AP22, AP21, AT21, AU25, AU26, AT23, AR26, AU24, AR23, AR28, AU23, AR22, AU20, AR18	O	GV _{DD}	—
MEMC1_MODT[0:1]	AG33, AJ36	O	GV _{DD}	6
MEMC1_MODT[2:3]/ MEMC2_MODT[0:1]	AT1, AK2	O	GV _{DD}	6
MEMC1_MWE	AT26	O	GV _{DD}	—
MEMC1_MRAS	AT29	O	GV _{DD}	—
MEMC1_MCAS	AT24	O	GV _{DD}	—
MEMC1_MCS[0:1]	AU27, AT27	O	GV _{DD}	—
MEMC1_MCS[2:3]/ MEMC2_MCS[0:1]	AU8, AU7	O	GV _{DD}	—

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LCLK[2]/LCS[7]	G37	O	OV _{DD}	—
LSYNC_OUT	F34	O	OV _{DD}	—
LSYNC_IN	G35	I	OV _{DD}	—
Programmable Interrupt Controller				
MCP_OUT	E34	O	OV _{DD}	2
IRQ0/MCP_IN	C37	I	OV _{DD}	—
IRQ[1]/M1SRCID[4]/M2SRCID[4]/LSRCID[4]	F35	I/O	OV _{DD}	—
IRQ[2]/M1DVAL/M2DVAL/LDVAL	F36	I/O	OV _{DD}	—
IRQ[3]/CORE_SRESET	H34	I/O	OV _{DD}	—
IRQ[4:5]	G33, G32	I/O	OV _{DD}	—
IRQ[6]/LCS[6]/CKSTOP_OUT	E35	I/O	OV _{DD}	—
IRQ[7]/LCS[7]/CKSTOP_IN	H36	I/O	OV _{DD}	—
DUART				
UART1_SOUT/M1SRCID[0]/M2SRCID[0]/LSRCID[0]	E32	O	OV _{DD}	—
UART1_SIN/M1SRCID[1]/M2SRCID[1]/LSRCID[1]	B34	I/O	OV _{DD}	—
UART1_CTS/M1SRCID[2]/M2SRCID[2]/LSRCID[2]	C34	I/O	OV _{DD}	—
UART1_RTS/M1SRCID[3]/M2SRCID[3]/LSRCID[3]	A35	O	OV _{DD}	—
I²C Interface				
IIC1_SDA	D34	I/O	OV _{DD}	2
IIC1_SCL	B35	I/O	OV _{DD}	2
IIC2_SDA	E33	I/O	OV _{DD}	2
IIC2_SCL	C35	I/O	OV _{DD}	2
QUICC Engine Block				
CE_PA[0]	F8	I/O	LV _{DD0}	—
CE_PA[1:2]	AH1, AG5	I/O	OV _{DD}	—
CE_PA[3:7]	F6, D4, C3, E5, A3	I/O	LV _{DD0}	—
CE_PA[8]	AG3	I/O	OV _{DD}	—
CE_PA[9:12]	F7, B3, E6, B4	I/O	LV _{DD0}	—
CE_PA[13:14]	AG1, AF6	I/O	OV _{DD}	—
CE_PA[15]	B2	I/O	LV _{DD0}	—
CE_PA[16]	AF4	I/O	OV _{DD}	—
CE_PA[17:21]	B16, A16, E17, A17, B17	I/O	LV _{DD1}	—

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LV _{DD0}	D5, D6	Power for UCC1 Ethernet interface (2.5 V, 3.3 V)	LV _{DD0}	—
LV _{DD1}	C17, D16	Power for UCC2 Ethernet interface option 1 (2.5 V, 3.3 V)	LV _{DD1}	9
LV _{DD2}	B18, E21	Power for UCC2 Ethernet interface option 2 (2.5 V, 3.3 V)	LV _{DD2}	9
V _{DD}	C36, D29, D35, E16, F9, F12, F15, F17, F18, F20, F21, F23, F25, F26, F29, F31, F32, F33, G6, J6, K32, M32, N6, P33, R6, R32, U32, V6, Y5, Y32, AB6, AB33, AD6, AF32, AK6, AL6, AM7, AM9, AM10, AM11, AM12, AM13, AM14, AM15, AM18, AM21, AM25, AM28, AM32, AN15, AN21, AN26, AU9, AU17	Power for core (1.2 V)	V _{DD}	—
OV _{DD}	A10, B9, B15, B32, C1, C12, C22, C29, D24, E3, E10, E27, G4, H35, J1, J35, K2, M4, N3, N34, R2, R37, T36, U2, U33, V4, V34, W3, Y35, Y37, AA1, AA36, AB2, AB34	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	—
MVREF1	AN20	I	DDR reference voltage	—
MVREF2	AU32	I	DDR reference voltage	—
SPARE1	B11	I/O	OV _{DD}	8
SPARE3	AH32	—	GV _{DD}	8
SPARE4	AU18	—	GV _{DD}	7
SPARE5	AP1	—	GV _{DD}	8

Table 66. MPC8360E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
No Connect				
NC	AM20, AU19	—	—	—

Notes:

1. This pin is an open drain signal. A weak pull-up resistor (1 k Ω) should be placed on this pin to OV_{DD}.
2. This pin is an open drain signal. A weak pull-up resistor (2–10 k Ω) should be placed on this pin to OV_{DD}.
3. This output is actively driven during reset rather than being three-stated during reset.
4. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
5. This pin should have a weak pull up if the chip is in PCI host mode. Follow PCI specifications recommendation.
6. These are On Die Termination pins, used to control DDR2 memories internal termination resistance.
7. This pin must always be tied to GND.
8. This pin must always be left not connected.
9. Refer to *MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual* section on “RGMII Pins,” for information about the two UCC2 Ethernet interface options.
10. It is recommended that MDIC0 be tied to GND using an 18.2 Ω resistor and MDIC1 be tied to DDR power using an 18.2 Ω resistor for DDR2.

This table shows the pin list of the MPC8358E TBGA package.

Table 67. MPC8358E TBGA Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DDR SDRAM Memory Controller Interface				
MEMC1_MDQ[0:63]	AJ34, AK33, AL33, AL35, AJ33, AK34, AK32, AM36, AN37, AN35, AR34, AT34, AP37, AP36, AR36, AT35, AP34, AR32, AP32, AM31, AN33, AM34, AM33, AM30, AP31, AM27, AR30, AT32, AN29, AP29, AN27, AR29, AN8, AN7, AM8, AM6, AP9, AN9, AT7, AP7, AU6, AP6, AR4, AR3, AT6, AT5, AR5, AT3, AP4, AM5, AP3, AN3, AN5, AL5, AN4, AM2, AL2, AH5, AK3, AJ2, AJ3, AH4, AK4, AH3	I/O	GV _{DD}	—
MEMC_MECC[0:4]/MSRCID[0:4]	AP24, AN22, AM19, AN19, AM24	I/O	GV _{DD}	—
MEMC_MECC[5]/MDVAL	AM23	I/O	GV _{DD}	—
MEMC_MECC[6:7]	AM22, AN18	I/O	GV _{DD}	—
MEMC_MDM[0:8]	AL36, AN34, AP33, AN28, AT9, AU4, AM3, AJ6, AP27	O	GV _{DD}	—
MEMC_MDQS[0:8]	AK35, AP35, AN31, AM26, AT8, AU3, AL4, AJ5, AP26	I/O	GV _{DD}	—
MEMC_MBA[0:1]	AU29, AU30	O	GV _{DD}	—
MEMC_MBA[2]	AT30	O	GV _{DD}	—
MEMC_MA[0:14]	AU21, AP22, AP21, AT21, AU25, AU26, AT23, AR26, AU24, AR23, AR28, AU23, AR22, AU20, AR18	O	GV _{DD}	—
MEMC_MODT[0:3]	AG33, AJ36, AT1, AK2	O	GV _{DD}	6

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LV _{DD1}	C17, D16	Power for UCC2 Ethernet interface option 1 (2.5 V, 3.3 V)	LV _{DD1}	9
LV _{DD2}	B18, E21	Power for UCC2 Ethernet interface option 2 (2.5 V, 3.3 V)	LV _{DD2}	9
V _{DD}	C36, D29, D35, E16, F9, F12, F15, F17, F18, F20, F21, F23, F25, F26, F29, F31, F32, F33, G6, J6, K32, M32, N6, P33, R6, R32, U32, V6, Y5, Y32, AB6, AB33, AD6, AF32, AK6, AL6, AM7, AM9, AM10, AM11, AM12, AM13, AM14, AM15, AM18, AM21, AM25, AM28, AM32, AN15, AN21, AN26, AU9, AU17	Power for core (1.2 V)	V _{DD}	—
OV _{DD}	A10, B9, B15, B32, C1, C12, C22, C29, D24, E3, E10, E27, G4, H35, J1, J35, K2, M4, N3, N34, R2, R37, T36, U2, U33, V4, V34, W3, Y35, Y37, AA1, AA36, AB2, AB34	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	—
MVREF1	AN20	I	DDR reference voltage	—
MVREF2	AU32	I	DDR reference voltage	—
SPARE1	B11	I/O	OV _{DD}	8
SPARE3	AH32	—	GV _{DD}	8
SPARE4	AU18	—	GV _{DD}	7
SPARE5	AP1	—	GV _{DD}	8

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

T_J = junction temperature (°C)

T_B = board temperature at the package perimeter (°C)

$R_{\theta JA}$ = junction to board thermal resistance (°C/W) per JESD51-8

P_D = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

22.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)

T_T = thermocouple temperature on top of package (°C)

Ψ_{JT} = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

22.2.4 Heat Sinks and Junction-to-Ambient Thermal Resistance

In some application environments, a heat sink is required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the airflow around the device, the interface material, the mounting arrangement on printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, airflow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

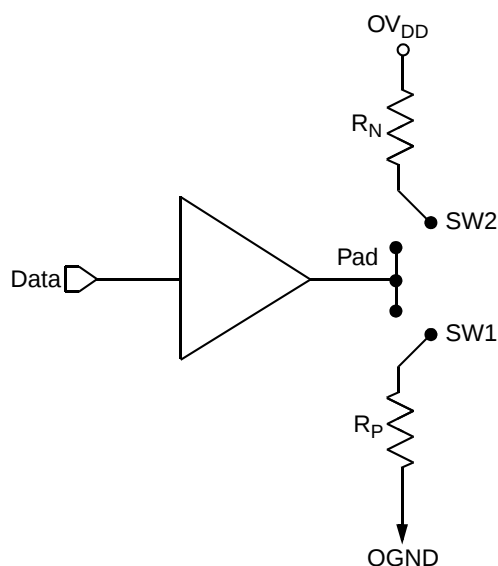


Figure 57. Driver Impedance Measurement

The value of this resistance and the strength of the driver's current source can be found by making two measurements. First, the output voltage is measured while driving logic 1 without an external differential termination resistor. The measured voltage is $V_1 = R_{\text{source}} \times I_{\text{source}}$. Second, the output voltage is measured while driving logic 1 with an external precision differential termination resistor of value R_{term} . The measured voltage is $V_2 = 1/(1/R_1 + 1/R_2) \times I_{\text{source}}$. Solving for the output impedance gives $R_{\text{source}} = R_{\text{term}} \times (V_1/V_2 - 1)$. The drive current is then $I_{\text{source}} = V_1/R_{\text{source}}$.

This table summarizes the signal impedance targets. The driver impedance are targeted at minimum V_{DD} , nominal OV_{DD} , 105° C.

Table 79. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	PCI	DDR DRAM	Symbol	Unit
R_N	42 Target	25 Target	20 Target	Z_0	W
R_P	42 Target	25 Target	20 Target	Z_0	W
Differential	NA	NA	NA	Z_{DIFF}	W

Note: Nominal supply voltages. See Table 1, $T_J = 105^\circ \text{C}$.

23.6 Configuration Pin Muxing

The device provides the user with power-on configuration options that can be set through the use of external pull-up or pull-down resistors of 4.7 k Ω on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{HRESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

Table 82. Revision History (continued)

Rev. Number	Date	Substantive Change(s)
3	03/2010	• Changed references to RCWH[PCICKEN] to RCWH[PCICKDRV]. • In Table 2, added extended temperature characteristics. • Added Figure 6, “DDR Input Timing Diagram.” • In Figure 53, “Mechanical Dimensions and Bottom Surface Nomenclature of the TBGA Package,” removed watermark. • Updated the title of Table 19, “DDR SDRAM Input AC Timing Specifications.” • In Table 20, “DDR and DDR2 SDRAM Input AC Timing Specifications Mode,” changed table subtitle. • In Table 27–Table 30, and Table 33–Table 34, changed the rise and fall time specifications to reference 20–80% and 80–20% of the voltage supply, respectively. • In Table 38, “IEEE 1588 Timer AC Specifications,” changed first parameter to “Timer clock frequency.” • In Table 45, “I2C AC Electrical Specifications,” changed units to “ns” for t_{I2DVKH}. • In Table 66, “MPC8360E TBGA Pinout Listing,” and Table 67 “MPC8358E TBGA Pinout Listing,” added note 7: “This pin must always be tied to GND” to the TEST pin and added a note to SPARE1 stating: “This pin must always be left not connected.” • In Section 4, “Clock Input Timing,” added note regarding rise/fall time on QUICC Engine block input pins. • Added Section 4.3, “Gigabit Reference Clock Input Timing.” • Updated Section 8.1.1, “10/100/1000 Ethernet DC Electrical Characteristics.” • In Section 20.3, “Pinout Listings,” added sentence stating “Refer to AN3097, ‘MPC8360/MPC8358E PowerQUICC Design Checklist,’ for proper pin termination and usage.” • In Section 21, “Clocking,” removed statement: “The OCCR[PCICDn] parameters select whether CLKIN or CLKIN/2 is driven out on the PCI_CLK_OUTn signals.” • In Section 21.1, “System PLL Configuration,” updated the system VCO frequency conditions. • In Table 80, added extended temperature characteristics.
2	12/2007	Initial release.